

Supervised Conformance Checking using Recurrent Neural Network Classifiers



ML4PM

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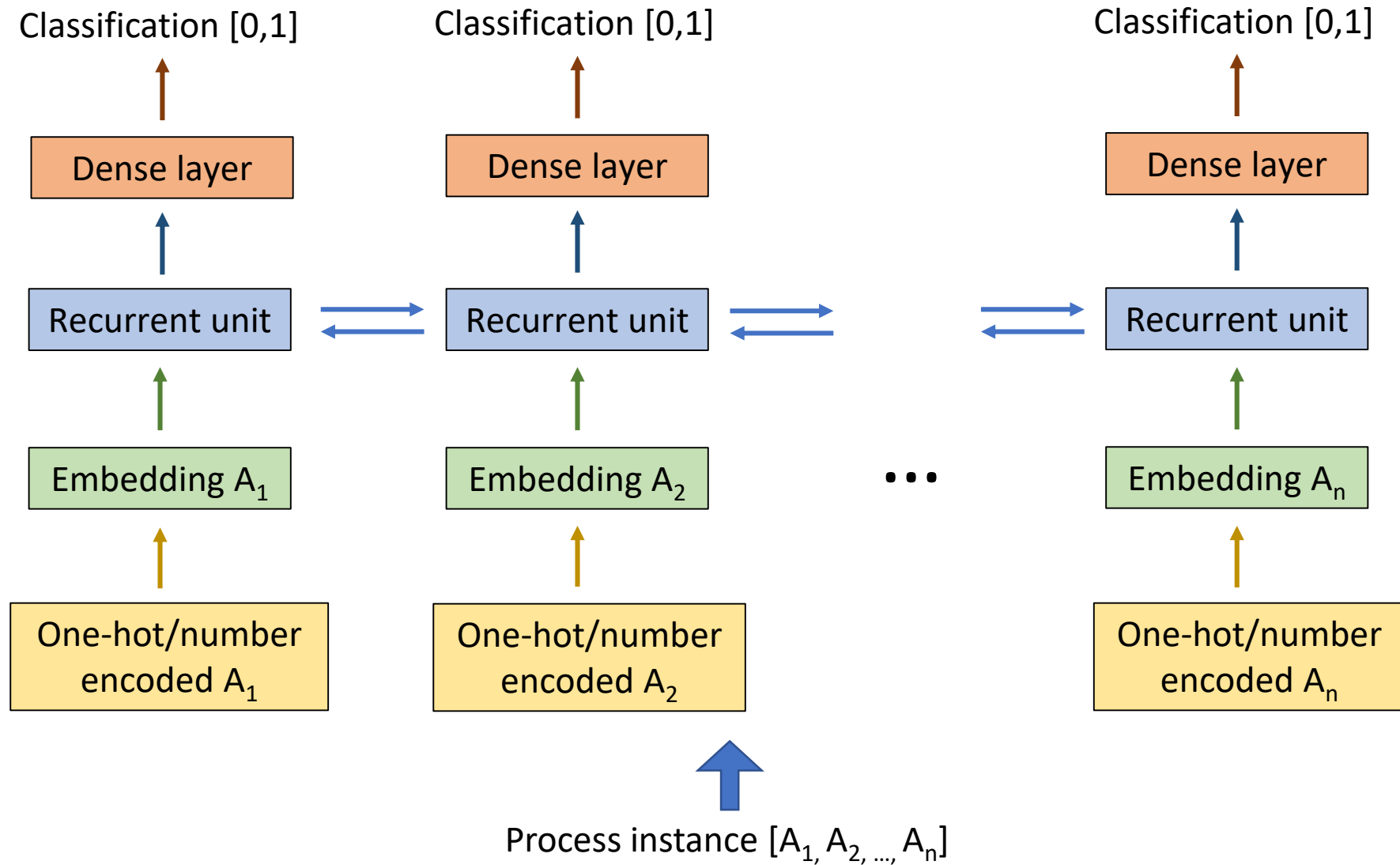
Process mining – Conformance checking

- How well does a certain model describe a certain log?
 - Global or local
- New conformance checking technique
 - Recall and Precision
 - Data driven
 - “Antilog“
 - Recurrent Neural Network

Recurrent Neural Network (RNN)

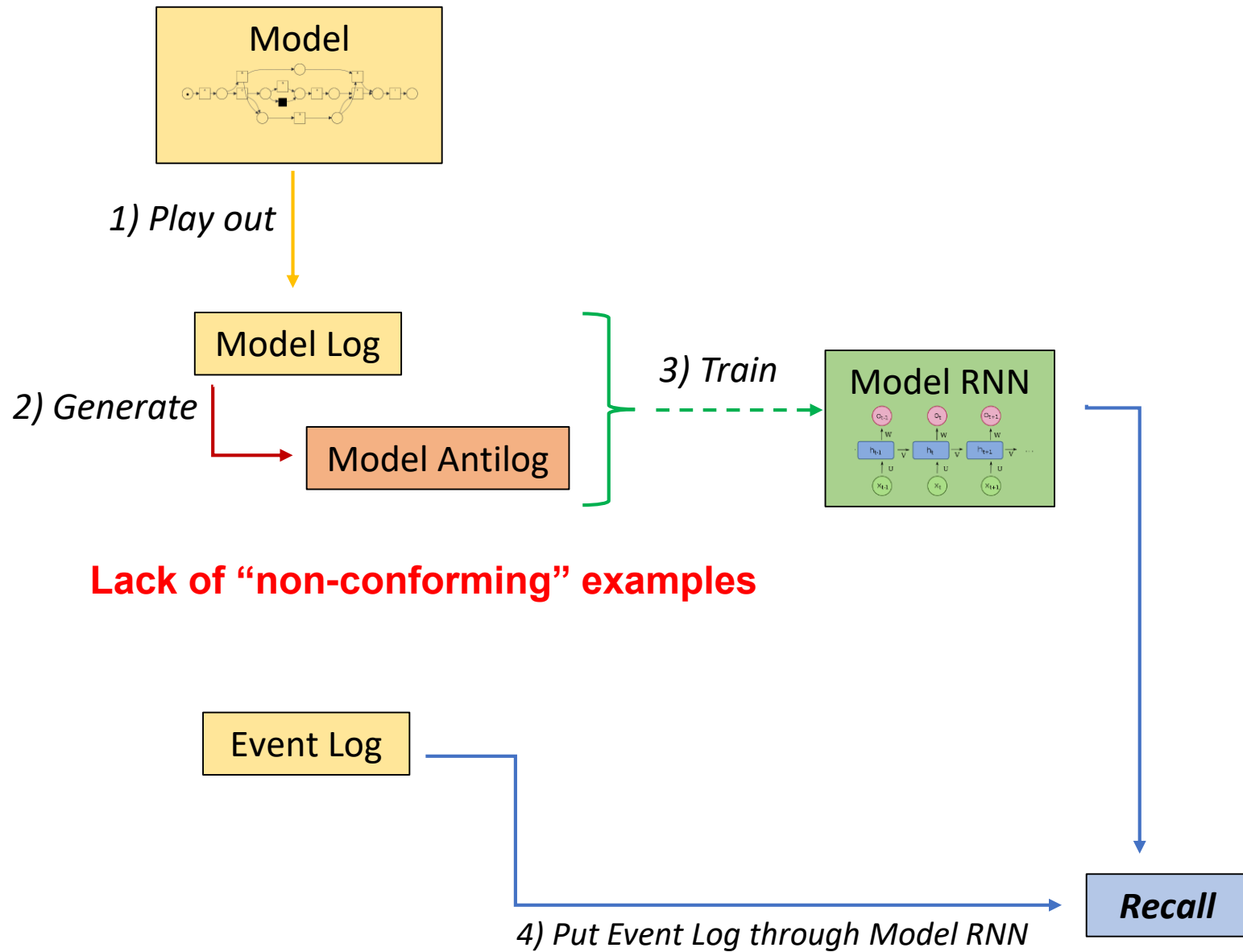
- Artificial neural network
- Sequential data
- Connected hidden layer
 - One- or bi-directional
- Simple RNN/LSTM/GRU

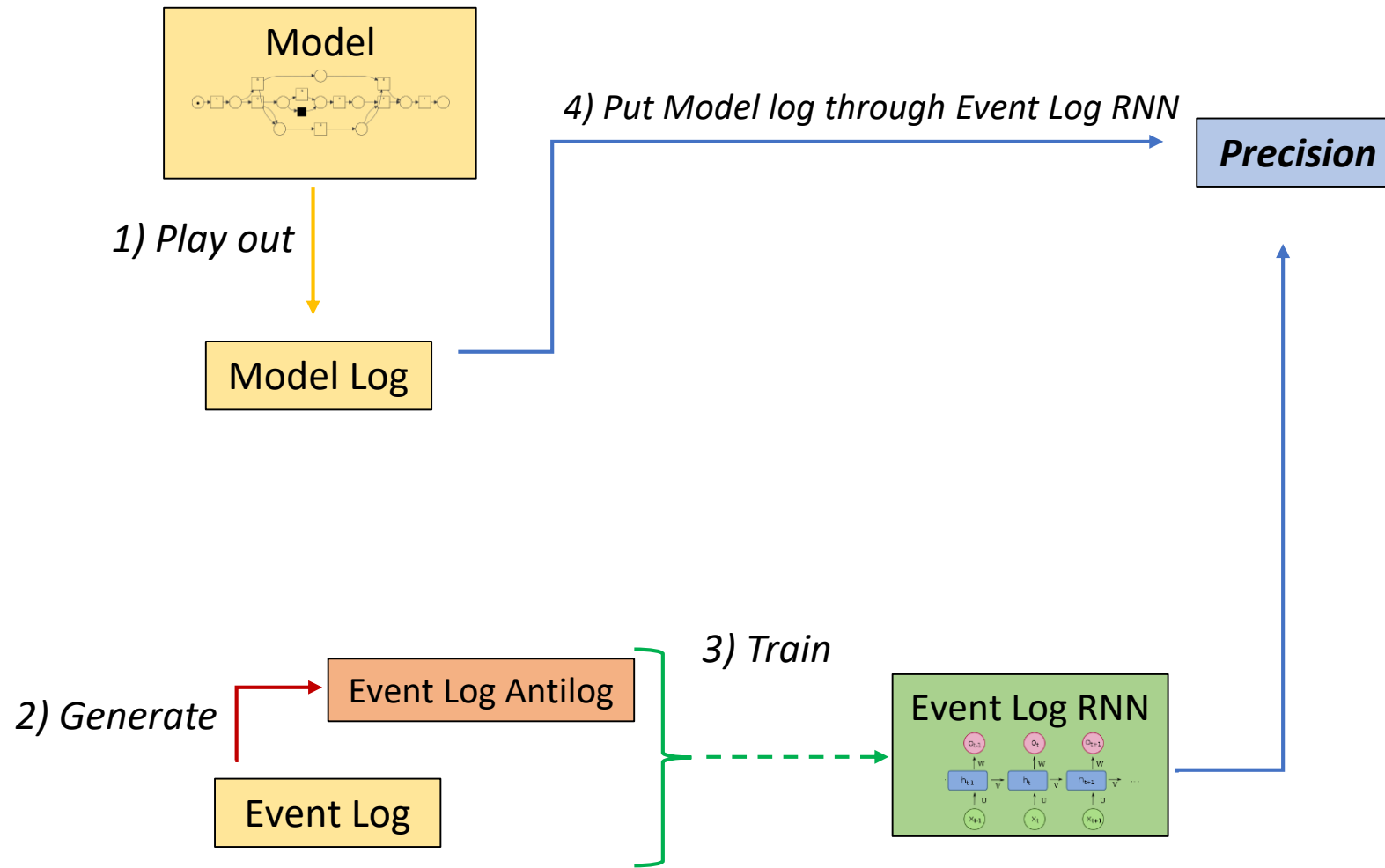
Local conformance?

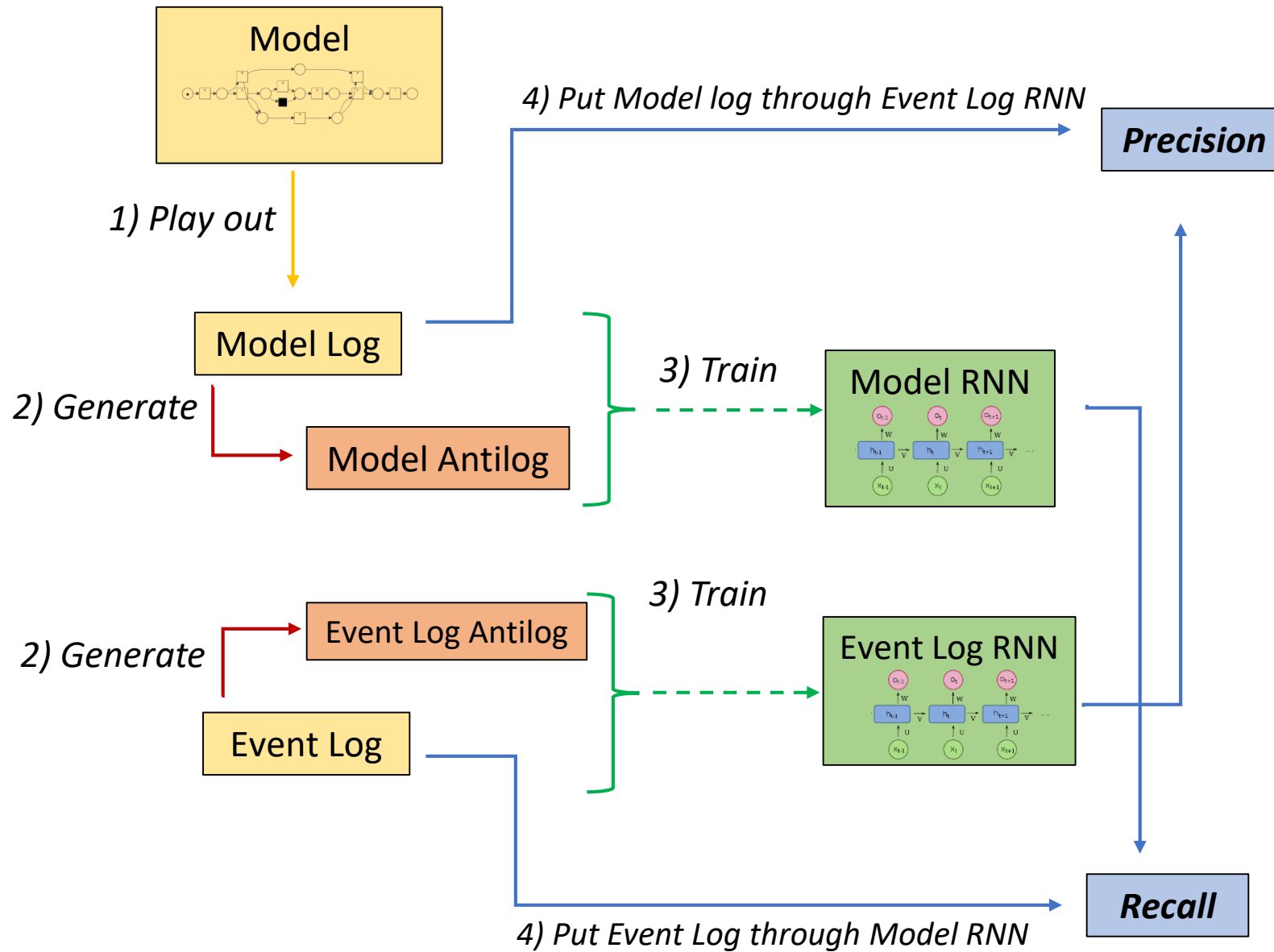


Our technique

- Depends on model simulation
 - Model log
- Antilog generation
 - Capture non-conforming behavior \approx negative traces
 - Random
 - Other possibilities
- RNN
 - Train on either Real Event Log or Model Log
 - Use output of the other log
- Average output value over all instances (**Prob.**) or % of traces higher than threshold (**Count**)







Testing

- Proof of concept global recall/precision

- Different models
 - With different recall/precision

- Discovered models

- Compared with literature (alignment based recall and precision, behavioral recall and precision and Markovian recall and precision)

Instance	#
$\langle A, B, D, E, I \rangle$	1207
$\langle A, C, D, G, H, F, I \rangle$	145
$\langle A, C, G, D, H, F, I \rangle$	56
$\langle A, C, H, D, F, I \rangle$	23
$\langle A, C, D, H, F, I \rangle$	28

Model	Recall					Precision				
	Prob.	Count	[1]	[13]	[3]	Prob.	Count	[1]	[27]	[3]
1	1.00 ± 0.00	1.00 ± 0.00	1.00	1.00	1.00	1.00 ± 0.04	1.00 ± 0.03	0.98	1.00	0.88
2	0.83 ± 0.00	0.83 ± 0.00	0.92	0.81	0.23	1.00 ± 0.00	1.00 ± 0.00	1.00	0.89	1.00
3	0.79 ± 0.01	1.00 ± 0.00	1.00	1.00	1.00	0.00 ± 0.00	0.00 ± 0.00	0.14	0.12	0.00
4	1.00 ± 0.00	1.00 ± 0.00	1.00	0.99	1.00	1.00 ± 0.01	1.00 ± 0.00	1.00	0.94	1.00
5	1.00 ± 0.00	1.00 ± 0.05	1.00	1.00	1.00	0.91 ± 0.02	0.89 ± 0.02	0.95	0.95	0.56
6	1.00 ± 0.00	1.00 ± 0.00	1.00	1.00	1.00	0.77 ± 0.01	0.77 ± 0.02	0.95	0.87	0.18
7	1.00 ± 0.00	1.00 ± 0.00	1.00	1.00	1.00	0.58 ± 0.04	0.60 ± 0.06	0.80	0.72	0.35
8	0.52 ± 0.02	0.52 ± 0.14	0.74	1.00	1.00	0.00 ± 0.00	0.00 ± 0.00	0.34	0.16	0.01
9	1.00 ± 0.00	1.00 ± 0.00	1.00	1.00	—	0.50 ± 0.01	0.50 ± 0.01	0.84	0.60	—
10	0.43 ± 0.11	0.45 ± 0.15	0.62	0.59	0.09	0.00 ± 0.00	0.00 ± 0.00	0.89	0.19	0.06
11	0.15 ± 0.01	0.17 ± 0.02	0.62	0.35	0.64	1.00 ± 0.01	1.00 ± 0.00	1.00	0.36	1.00
Alpha	0.96 ± 0.00	0.97 ± 0.00	1.00	0.99	0.77	0.73 ± 0.01	0.72 ± 0.01	0.96	0.92	0.38
Ind. 0	1.00 ± 0.00	1.00 ± 0.00	1.00	1.00	1.00	0.86 ± 0.04	0.89 ± 0.05	0.72	0.59	0.42
Ind. 0.5	1.00 ± 0.00	1.00 ± 0.00	1.00	0.99	0.77	0.84 ± 0.03	0.86 ± 0.04	0.79	0.69	0.44
Ind. 1	0.18 ± 0.11	0.17 ± 0.12	0.86	0.84	0.68	0.82 ± 0.06	0.81 ± 0.07	0.87	0.64	0.48

- Agrees with literature on most models
- Potential issues with overly general models (e.g. model 3 = flower)
 - Model simulation
- Other differences with literature
 - Our method puts more emphasis on most prevalent variant
- Model log can be expanded
 - Antilog should be big enough

Other potential uses

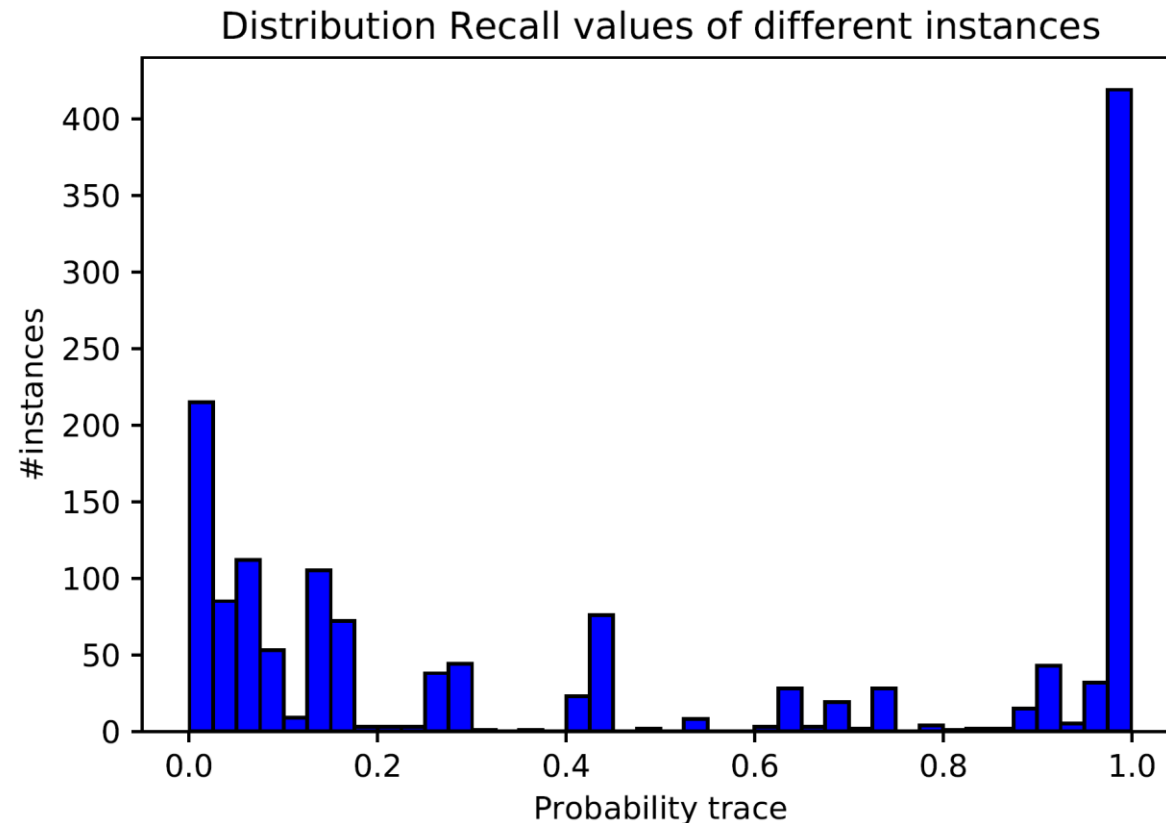
- Using the output at each timestep to identify where the non-conforming behavior is detected.

<i>Trace</i>	A	B	D	E	I
<i>Alignment</i>	A	B	D	E	I
<i>Output</i>	0.0	0.0	0.02	0.71	0.99

<i>Trace</i>	A	B	D	E	A	I
<i>Alignment</i>	A	B	D	E	>>	I
<i>Output</i>	0.0	0.0	0.02	0.68	0.0	0.3

Other potential uses

- Probability distribution
 - Individual probabilities for each instance

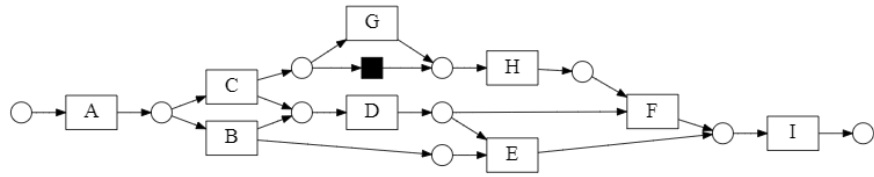


Conclusion

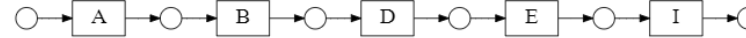
- New data-driven conformance checking technique
- Based on model simulation, random antilog generation and RNN's
- Quick (once trained)
- Shows potential for global conformance analysis

Future work

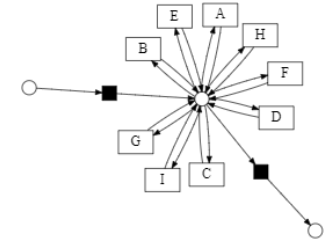
- Further local conformance possibilities
- Explore alternative antilogs
 - Negative events, noise...
- Include additional data attributes
- Directly rely on the given process model



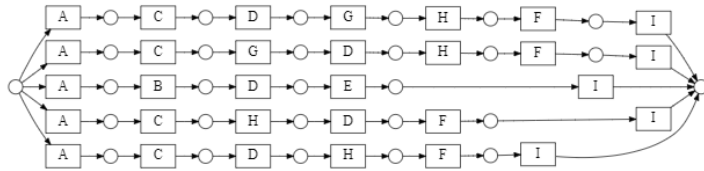
Model 1: fitting and good precision [1].



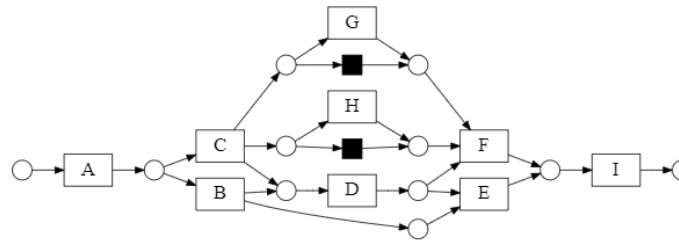
Model 2: single most frequent trace [1].



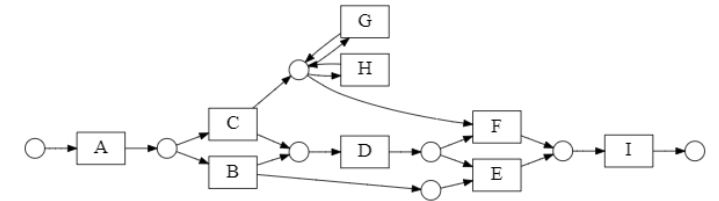
Model 3: flower model [1].



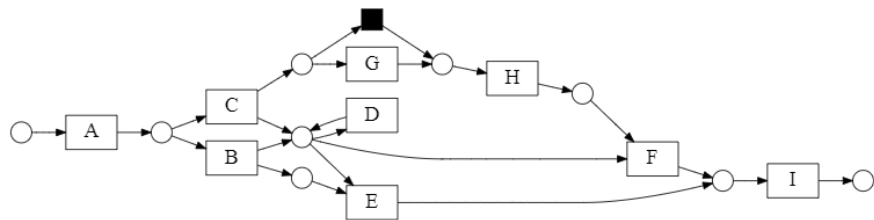
Model 4: all traces in parallel [1].



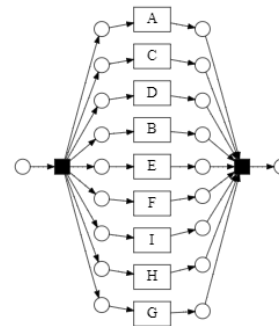
Model 5: G and H in parallel [1].



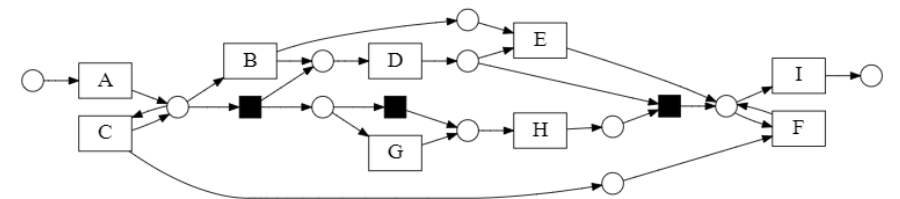
Model 6: G and H in self-loops [1].



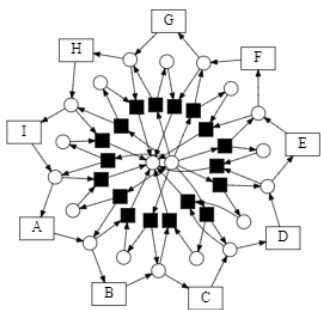
Model 7: D in a self-loop [1].



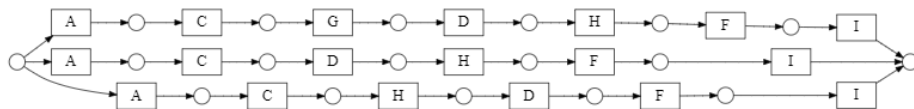
Model 8: all transitions in parallel [1].



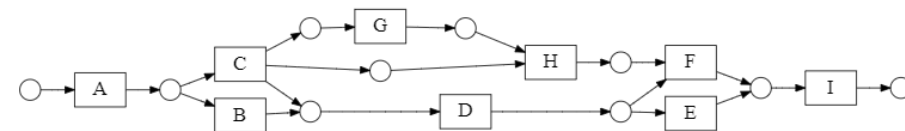
Model 9: C and F are in a loop and need to be executed the same amount to reach the final marking [1].



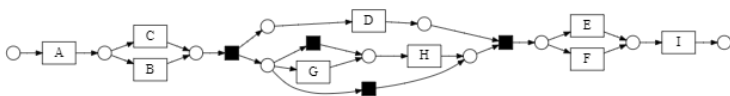
Model 10: Round-robin model [1].



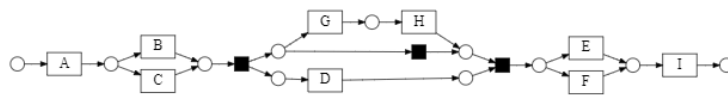
Model 11: 3 least common traces in parallel.



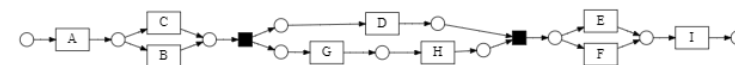
Model alpha: discovered by alpha miner [8] using the log in Table I.



Model Ind. 0: discovered by inductive miner with noise set to 0 [9] using the log in Table I.



Model Ind. 0.5: discovered by inductive miner with noise set to 0.5 [9] using the log in Table I.



Model Ind. 1: discovered by inductive miner with noise set to 1 [9] using the log in Table I.